

Structural Effect of Carbon on Mn₅Ge₃ Thin Films Grown on Ge(001) Substrates by Solid Phase Epitaxy

Adriana Alvídrez-Lechuga¹, Sion Olive-Méndez¹, Luis Fuentes-Cobas², José Holguín-Momaca¹ and Jasper Plaisier³

¹Centro de Investigación en Materiales Avanzados S.C., United States, ²Centro de Investigación en Materiales Avanzados, United States, ³Elettra - Sincrotrone Trieste, United States

Spintronic devices take advantage of the electron spin, considered as an additional degree of freedom. One of the challenges on the design of spintronic devices, as the spin-field effect transistor, is the achievement of spin injection into IV-group semiconductors via a Schottky barrier at room temperature (RT) [1]. Mn₅Ge₃ compound is the only FM phase with a Curie temperature (TC) of 296 K, has been found that TC increases with carbon doping [2]. Mn₅Ge₃ has a hexagonal crystal structure P6₃/mcm and lattice constants $a = 7.184 \text{ \AA}$ and $c = 5.053 \text{ \AA}$, these characteristics allow the growth on Ge(111) substrates within a lattice mismatch of 3.7% [3]. However, Ge(111) is not compatible with the Si(001) technology, while Ge(001)/Mn₅Ge₃ heterostructures offer a good possibility for the design of spintronic devices. In this work, we present the growth of Ge(001)/Mn₅Ge₃ thin films using the solid phase epitaxy (SPE) method, samples doped with carbon atoms and without carbon were grown by magnetron-sputtering technique. Carbon doping has been found to affect the arrangement of the atomic structure. The SPE method consists of the deposition of Mn or co-deposition of Mn and Ge at room temperature (RT) followed by thermal annealing at $T_s = 250 \text{ }^\circ\text{C}$ to induce Ge diffusion into the Mn layer to form the Mn₅Ge₃ layer.

Figure 1 shows the bi-dimensional grazing incidence x-ray diffraction (2D-GIXRD) pattern collected for a sample doped with carbon. The pattern shows discontinuous Debye rings that are associated with the texture, there are observed four peaks at 20.4, 28.3, 35.0, and 40.5° corresponding to the (102), (4-21), (5-21), and (5-12) reflections from the Mn₅Ge₃ compound. The reflection Ge(311) corresponds to the substrate. The indexation was based on the ICSD #156103 crystallographic datasheet. Figure 2(a) shows the HRTEM micrograph for the sample without carbon, the c-axis of the Mn₅Ge₃ unit cell is normal to the Ge(001) plane of the substrate. The interface is relatively abrupt at the atomic scale along with a few atomic layers. The sample doped with carbon, figure 2(b), shows two stages of epitaxial growth: first, an Mn deposition, where the c-axis is normal to the Ge(001) plane, but the atomic arrangement is different from that in figure 2(a). In the Mn and Ge co-deposition stage, the c-axis of the Mn₅Ge₃ unit cell forms an angle with the plane of the substrate surface.

The authors thank the financial support obtained from Ciencia-Básica SEP-CONACYT grant No. 157559 and Fondo Mixto Chihuahua FOMIX grant No. CHIH-2011-C03-1688. The authors thank the beamtime at the beamline 7.1 MCX at Elettra Synchrotron to perform the 2D-GIXRD measurements.

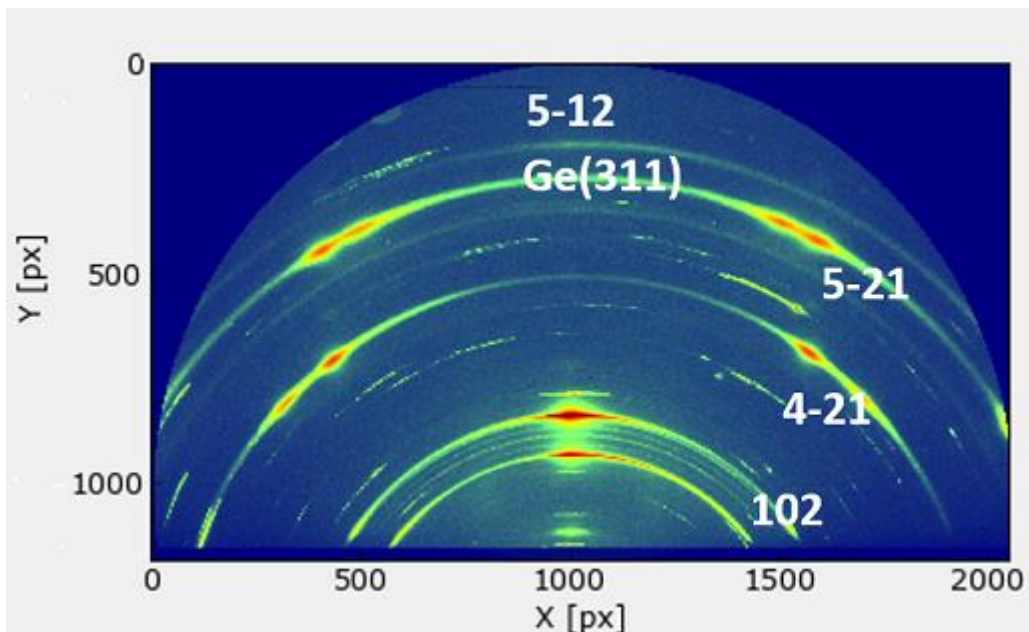


Figure 1. 2D-GIXRD for a simple with carbon, where the indexed Debye rings belong to the Mn_5Ge_3 .

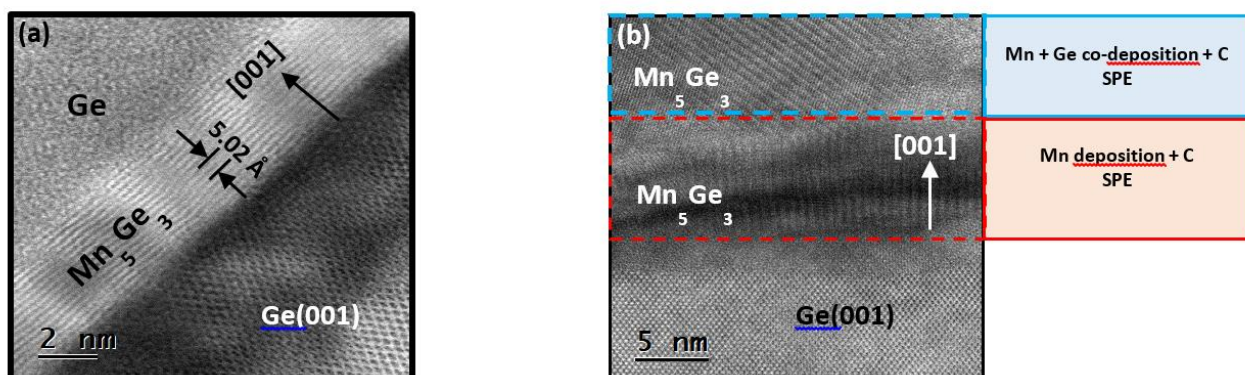


Figure 2. HR-TEM micrographs of Mn_5Ge_3 samples: (a) without carbon and (b) with carbon.

References

- [1] A. Spiesser, H. Saito, R. Jansen, S. Yuasa, K. Ando, Large spin accumulation voltages in epitaxial Mn_5Ge_3 contacts on Ge without an oxide tunnel barrier, *Phys. Rev. B* 90 (2014) 205213.
- [2] O. Abbes, A. Portavoce, V. Le Thanh, C. Girardeaux, L. Michez, Phase formation during Mn thin film reaction with Ge: Self-aligned germanide process for spintronics, *Appl. Phys. Lett.* 103 (2013) 172405.
- [3] C. Zeng, S.C. Erwin, L.C. Feldman, A.P. Li, R. Jin, Y. Song, J.R. Thompson, H. H. Weiering, Epitaxial ferromagnetic Mn_5Ge_3 on Ge(111), *Appl. Phys. Lett.* 83 (2003) 5002.